

<p style="text-align: center;">OCT 14 2003 U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE JAN 14 2004 LIST OF REFERENCES CITED BY APPLICANT(S) (Use several sheets if necessary)</p>			ATTY DOCKET NO. 03500.017504		APPLICATION NO. 10/647,287		
			APPLICANTS MITSUTOSHI HASEGAWA ET AL.				
			FILING DATE August 26, 2003		GROUP n/y/a		
U.S. PATENT DOCUMENTS							
*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
KR		6,060,113	05/00	Banno et al.	427	125	
		6,296,896 B1	10/01	Takahashi et al.	427	77	
		2003/0067263 A1	04/03	Tokioka et al.	313	493	08/28/02
		6,624,586 B2	09/03	Abe et al.	315	169.1	
		5,455,597	10/95	Nakamura et al.	345	75	
		5,659,329	08/97	Yamanobe et al.	345	74	
KR		6,137,218	10/00	Kaneko et al.	313	495	
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		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO/ OR ABSTRACT
JP		7-326311	12/95	Japan			Abstract
JP		8-185818	07/96	Japan			Abstract
JP		9-50757	02/97	Japan			Abstract
JP		9-102271	04/97	Japan			Abstract
JP		2000-251665	9/00	Japan			Abstract
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		M. Hartwell et al, "Strong electron emission from patterned tin-indium oxide thin films", International Electron Devices Meeting 1975, Washington, D.C., Catalog No. 75, CH1023-1, IEDM Technical Digest, pp. 519-521.					
EXAMINER		DATE CONSIDERED 4/5/05					

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APPLICANT

MITSUTOSHI HASEGAWA ET AL.

FILING DATE

August 26, 2003

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JP	11-135018	05/99	Japan			Abstract
JPP	2001-210258	8/01	Japan			Abstract

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EXAMINER <i>M. Hase</i>	DATE CONSIDERED	4/5/05

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